

Notice of References Cited	Application/Control No. 10/508,793		Applicant(s)/Patent Under Reexamination OHBA ET AL.	
	Examiner Allen C. Ho		Art Unit 2882	Page 1 of 1

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*	B	US-6,278,764 B1	08-2001	Barbee et al.	378/84
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*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)
Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.